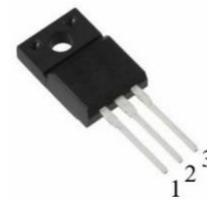


**Description**

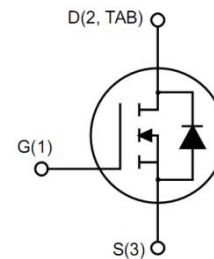
Silicon Carbide (SiC) MOSFET use a completely new technology that provide superior switching performance and higher reliability compared to Silicon. In addition, the low ON resistance and compact chip size ensure low capacitance and gate charge. Consequently, system benefits include highest efficiency, faster operating frequency, increased power density, reduced EMI, and reduced system size.

**Features**

- High Speed Switching with Low Capacitances
- AST Technology with 12V Gate Drive
- Lower  $Q_G$  and Device Capacitances( $C_{oss}, C_{rss}$ )
- Body Diode with Low  $V_F$  and Low  $Q_{RR}$
- Faster and More Efficient Switching
- ROHS Compliant, Halogen free


**Application**

- Solar String Inverter and Central Inverter
- UPS
- Switch Mode Power Supplies
- Power Factor Correction Modules
- Battery Charging
- Auxiliary Power Supply
- High Voltage Converter


**Ordering Information**

Part Number	Marking	Package	Packaging
A3G1N1700MF3	A3G1N1700MF3	TO-220F	Tube

**Absolute Maximum Ratings(Tc=25°C)**

Symbol	Parameter	Value	Unit
V <sub>DS</sub>	Drain-Source Voltage	1700	V
I <sub>D</sub>	Drain Current(continuous)at Tc=25°C	1	A
I <sub>D</sub>	Drain Current(continuous)at Tc=100°C	0.5	A
I <sub>DM</sub>	Drain Current (pulsed)	2	A
V <sub>GS</sub>	Gate-Source Voltage	-5/+15	V
P <sub>D</sub>	Power Dissipation T <sub>C</sub> = 25°C	20	W
T <sub>J</sub> , T <sub>stg</sub>	Junction and Storage Temperature Range	-55 to +175	°C

**Electrical Characteristics(T<sub>J</sub> = 25°C unless otherwise specified)**
**Typical Performance-Static**

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
BV <sub>DS</sub>	Drain-source Breakdown Voltage	I <sub>D</sub> =100uA, V <sub>GS</sub> =0V	1700			V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =1700V, V <sub>GS</sub> =0V, T <sub>J</sub> =25°C			10	uA
I <sub>GSS</sub>	Gate-body Leakage Current	V <sub>DS</sub> =0V ; V <sub>GS</sub> =-5 to 15V			250	nA
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> =200uA	1.5	2	3	V
V <sub>GSon</sub>	Recommended turn-on Voltage	Static		12		V
V <sub>GSoff</sub>	Recommended turn-off Voltage			-3		V
R <sub>DS(on)</sub>	Static Drain-source On Resistance	V <sub>GS</sub> =12V, I <sub>D</sub> =0.5A		10	15	Ω
		V <sub>GS</sub> =12V, I <sub>D</sub> =0.5A T <sub>J</sub> =175°C		18		Ω

**Typical Performance-Dynamic**

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> =1000V, f=1MHz, V <sub>GS</sub> =0V V <sub>AC</sub> =25mV		50		pF
C <sub>oss</sub>	Output Capacitance			2		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			0.5		pF
g <sub>fs</sub>	Transconductance	V <sub>DS</sub> =10V, I <sub>D</sub> =0.5A		0.3		S
E <sub>OSS</sub>	C <sub>OSS</sub> Stored Energy	V <sub>DS</sub> =1000V, f=1MHz		1.2		μJ
E <sub>ON</sub>	Turn-On Energy (Body Diode)	V <sub>DS</sub> =1200V, V <sub>GS</sub> =-3/12V, I <sub>D</sub> =0.5A, L=1mH T <sub>J</sub> =175°C R <sub>ext</sub> =25Ω		16		μJ
E <sub>OFF</sub>	Turn-Off Energy (Body Diode)			3.6		μJ
Q <sub>g</sub>	Total Gate Charge	V <sub>DS</sub> =1200V, V <sub>GS</sub> =-3V/12V, I <sub>D</sub> =0.5A		2.5		nC
Q <sub>gs</sub>	Gate-source Charge			0.4		nC
Q <sub>gd</sub>	Gate-Drain Charge			0.8		nC
t <sub>d(on)</sub>	Turn-on Delay Time	V <sub>DS</sub> =1200V, V <sub>GS</sub> =-3V/12V, I <sub>D</sub> =0.5A, L=1mH R <sub>ext</sub> =25Ω		2.6		ns
t <sub>r</sub>	Rise Time			1.7		ns
t <sub>d(off)</sub>	Turn-off Delay Time			2.2		ns
t <sub>f</sub>	Fall Time			1.5		ns

**Typical Performance-Reverse Diode(T<sub>J</sub> = 25°C unless otherwise specified)**

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
V <sub>FSD</sub>	Forward Voltage	V <sub>GS</sub> =0V, I <sub>F</sub> =0.2A, T <sub>J</sub> =25°C		3.5	6	V
		V <sub>GS</sub> =0V, I <sub>F</sub> =0.2A, T <sub>J</sub> =175°C		3	6	V
I <sub>S</sub>	Continuous Diode Forward Current	V <sub>GS</sub> =0V, T <sub>C</sub> =25°C				A

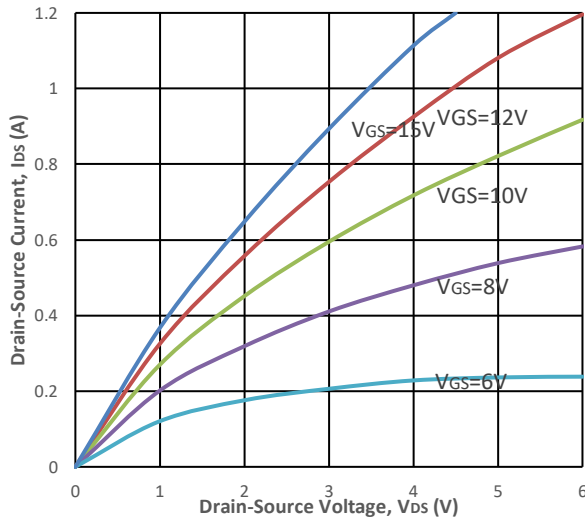
**Thermal Characteristics**

Symbol	Parameter	Value.	Unit
R <sub>θJC</sub>	Thermal Resistance, Junction-to-Case	7.5	°C/W
R <sub>θJA</sub>	Thermal Resistance, Junction-to-Ambient	40	°C/W

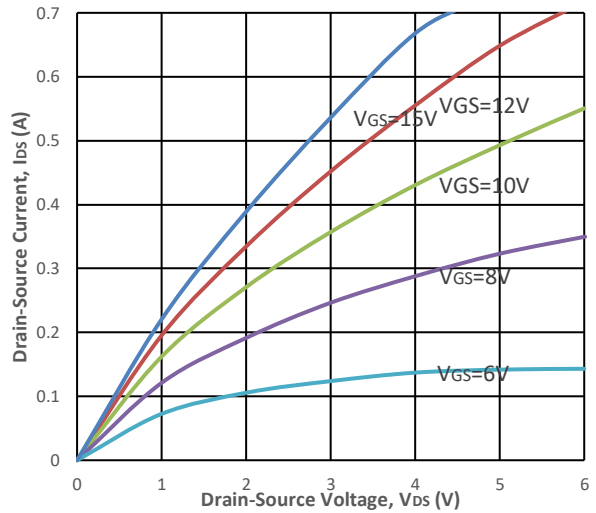
The values are based on the junction-to case thermal impedance which is measured with the device mounted to a large heat sink assuming maximum junction temperature of T<sub>J</sub>(max)=175°C

### Electrical Characteristics

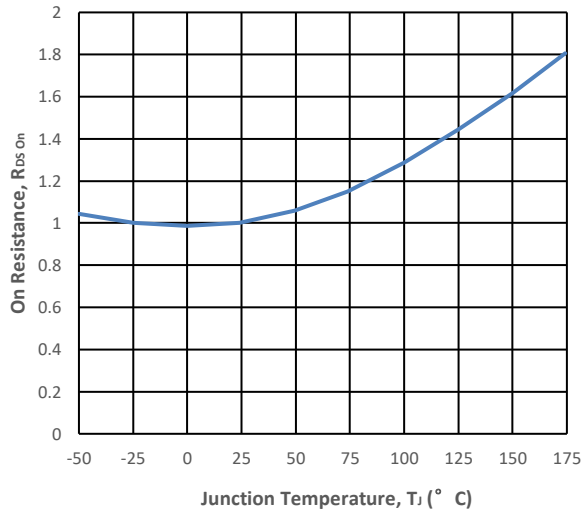
**Fig1. Output characteristics ( $T_J = 25^\circ\text{C}$ )**



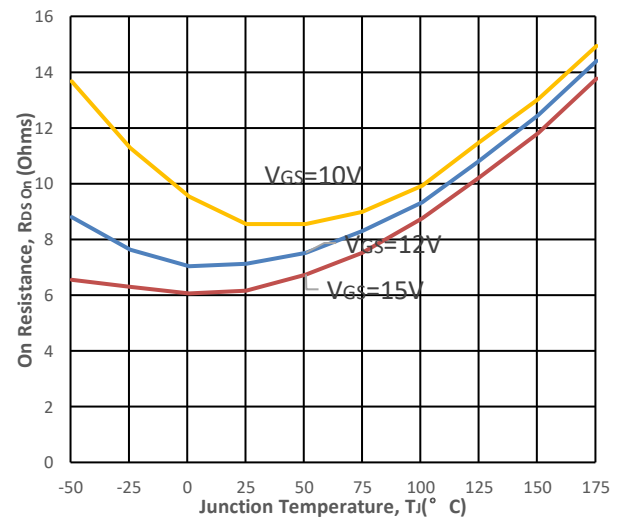
**Fig2. Output characteristics ( $T_J = 175^\circ\text{C}$ )**



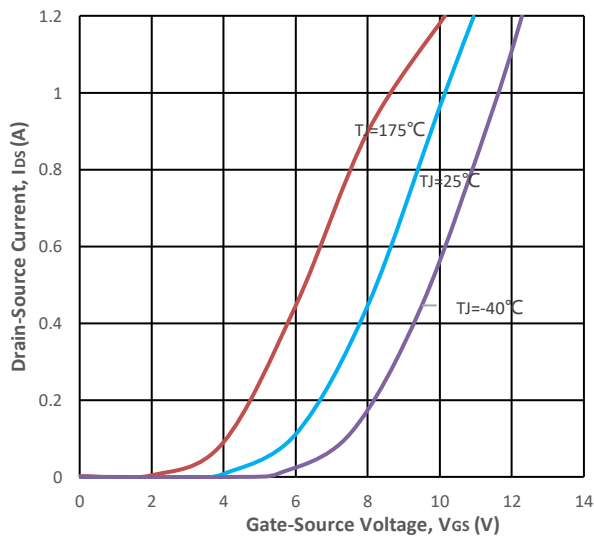
**Fig3. Normalized On-Resistance vs. Temperature**



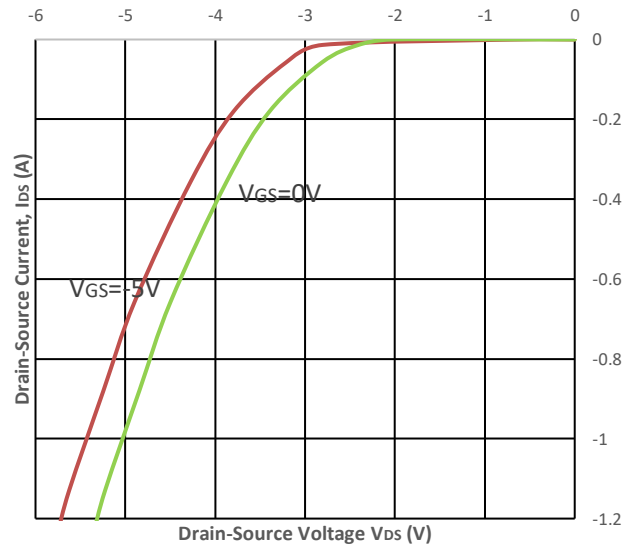
**Fig4. On-Resistance vs. Temperature**



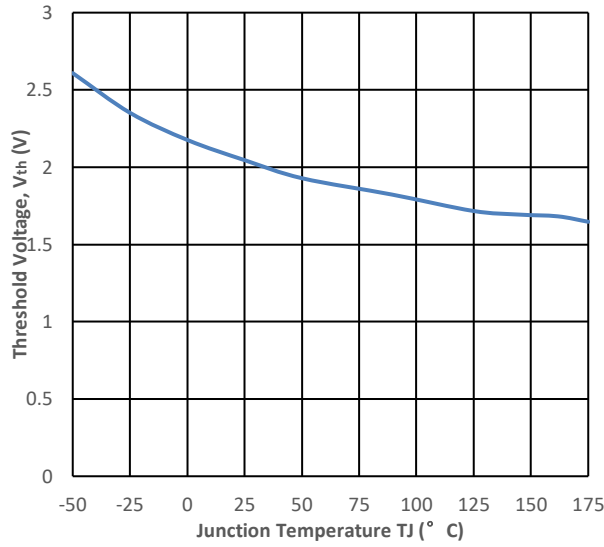
**Fig5. Transfer Characteristic**



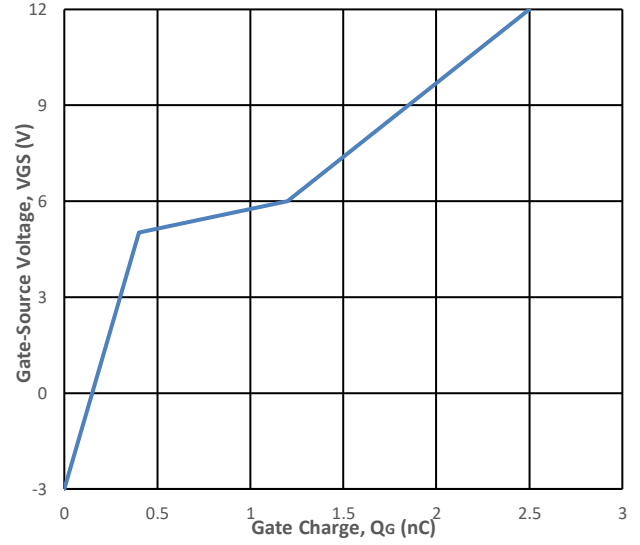
**Fig6. Body Diode Characteristic at 25 °C**



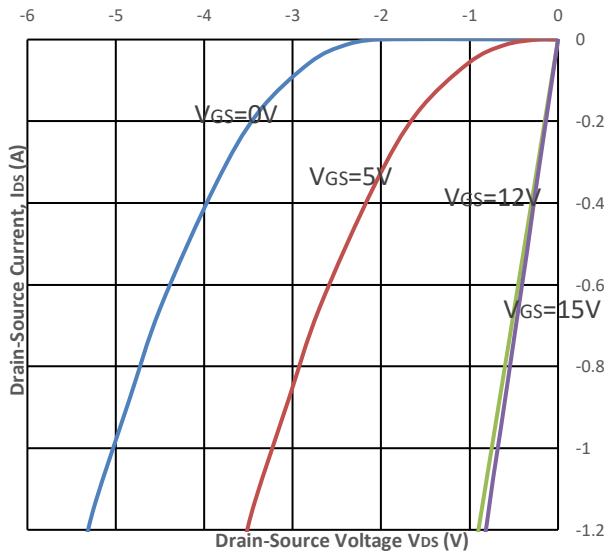
**Fig7. Threshold Voltage vs. Temperature**



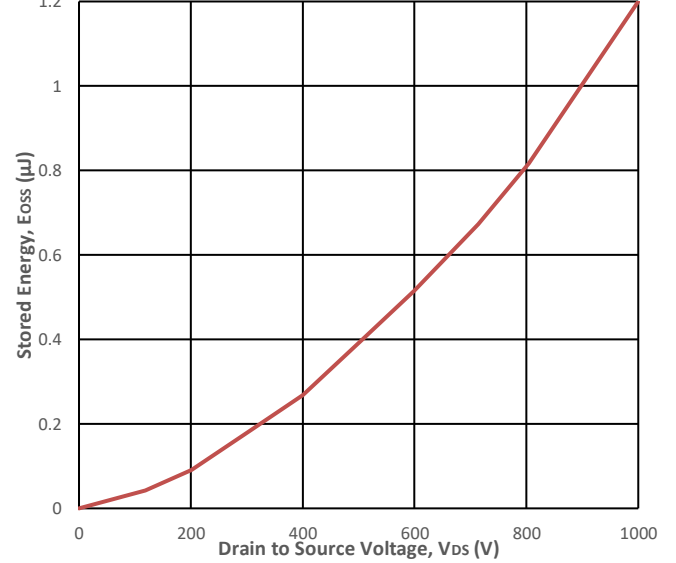
**Fig8. Gate Charge Characteristics**



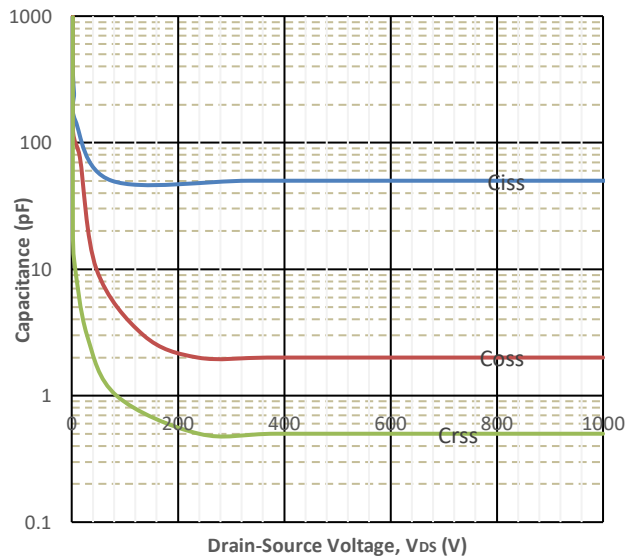
**Fig9. 3rd Quadrant Characteristic at 25 °C**



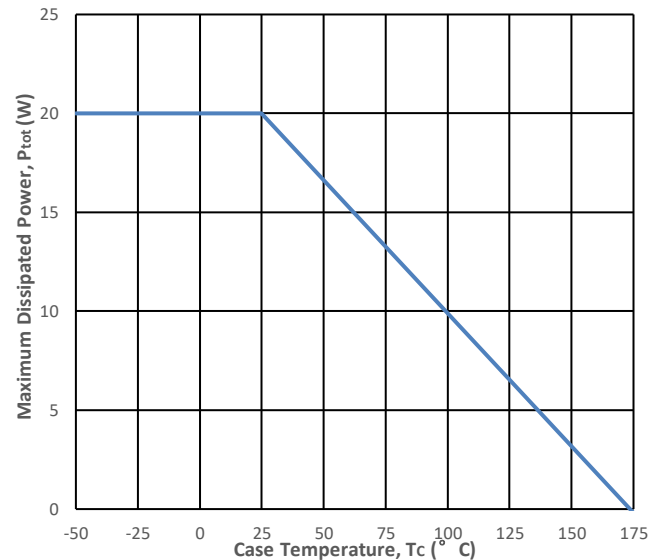
**Fig10. Output Capacitor Stored Energy**



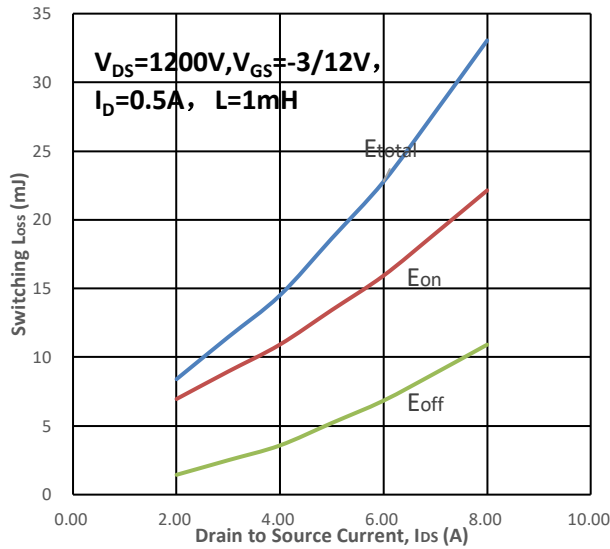
**Fig11. Capacitances vs. Drain-Source**



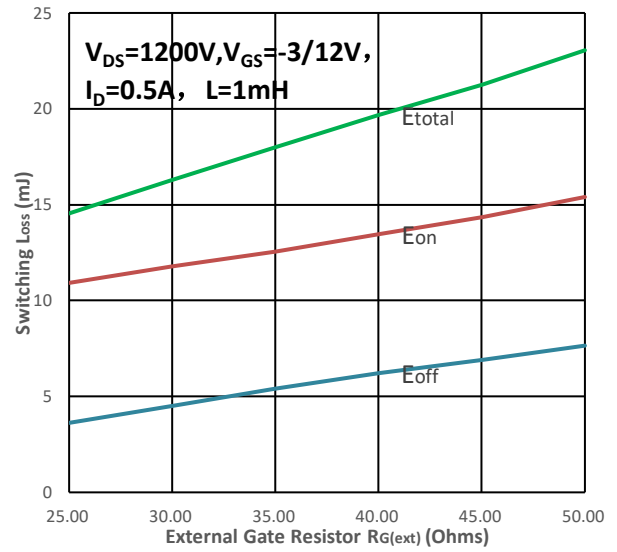
**Fig12. Max Power Dissipation Derating Vs  $T_c$**



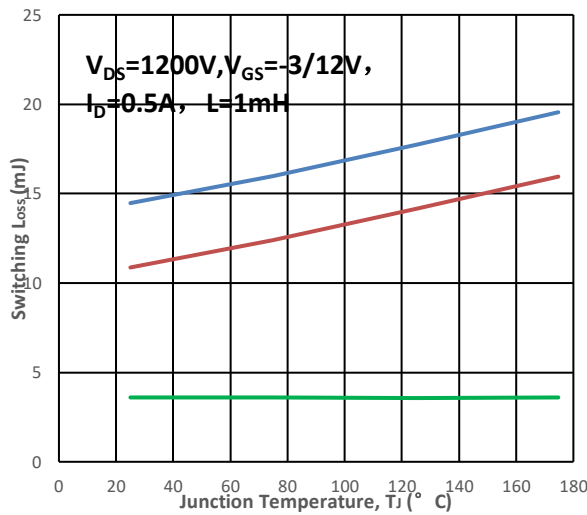
**Fig13. Switching Energy vs. Drain Current**



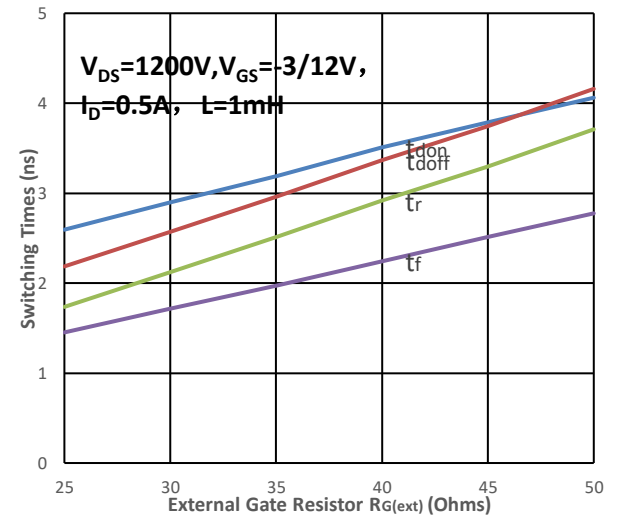
**Fig14. Switching Energy vs. RG(ext)**



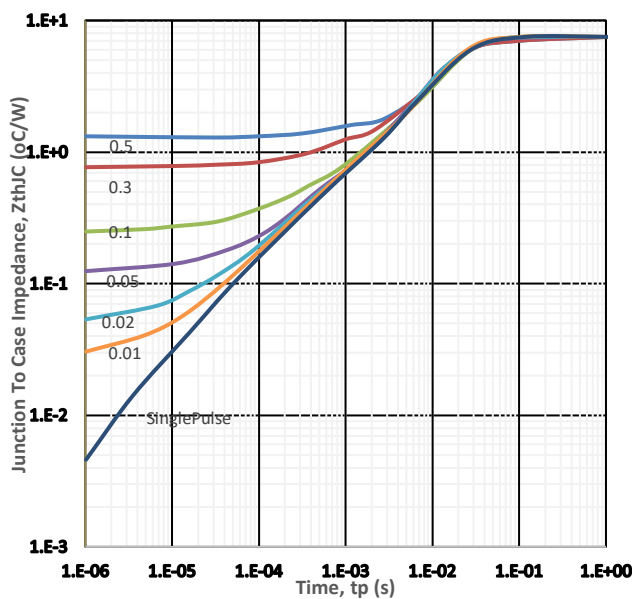
**Fig15. Switching Energy vs. Temperature**



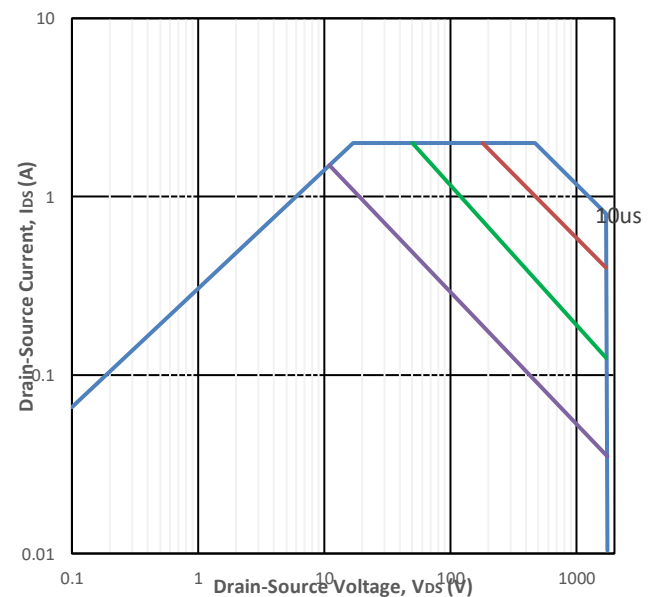
**Fig16. Switching Times vs. RG(ext)**



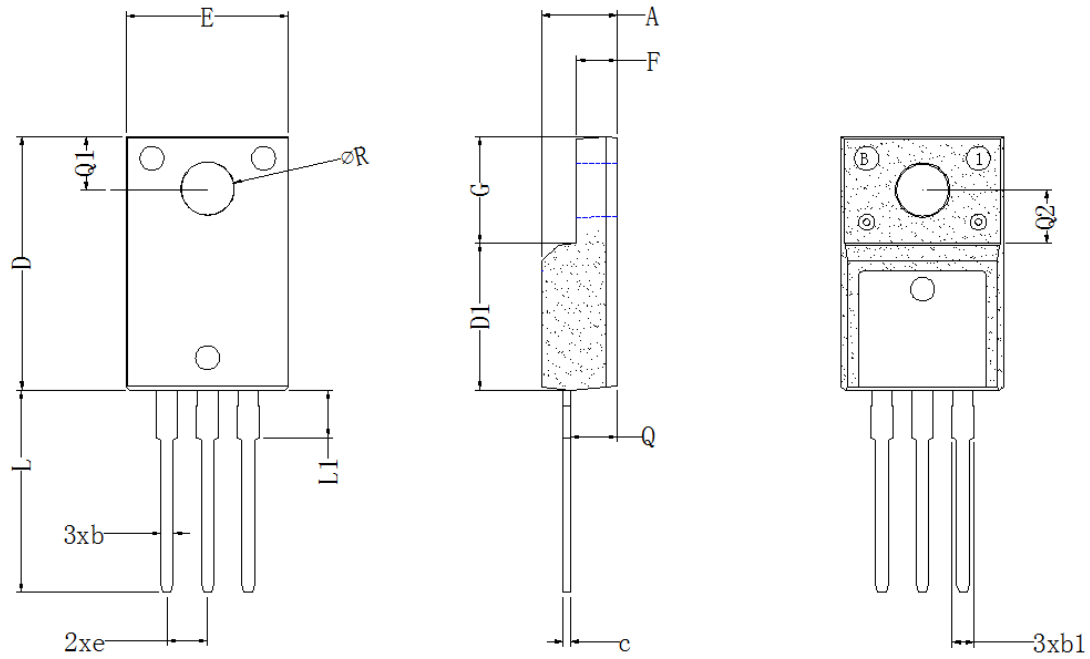
**Fig17. Transient Thermal Impedance**



**Fig18. Safe Operating Area**



### Package Drawing



### Dimensions ( UNIT: mm ) :

SYMBDLS	DIMENSIONS IN MILLIMETERS		
	MIN	NOM	MAX
A	4.50	4.70	4.90
b	0.60	0.80	1.00
b1	1.16	1.36	1.56
c	0.45	0.50	0.60
D	15.67	15.87	16.07
D1	8.99	9.19	9.39
e	2.04	2.54	3.04
E	9.86	10.16	10.46
F	2.34	2.54	2.74
G	6.48	6.68	6.88
L	12.48	12.68	12.88
L1	2.78	2.98	3.18
Q	2.70	2.90	3.10
Q1	3.15	3.35	3.55
Q2	3.13	3.33	3.53
$\varnothing R$	3.10	3.30	3.50